

Computational Modeling of Amorphous Materials

Brittany Hoard

Advisor: Dr. Blair Tuttle

Penn State Erie, The Behrend College

Outline

- Intro
- Amorphous Si
 - Goal: Determine point defects in solar cells
- Interfaces with amorphous materials
 - Goal: Structure of interface

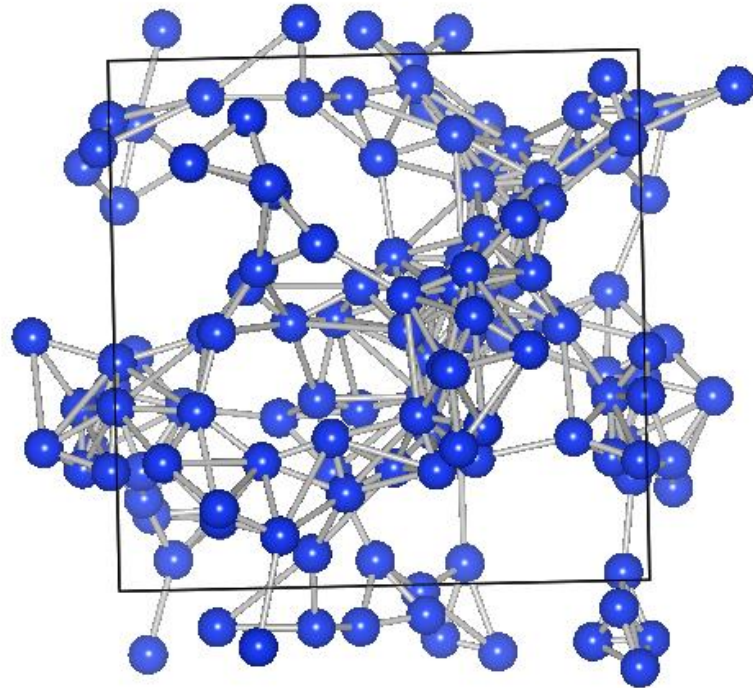
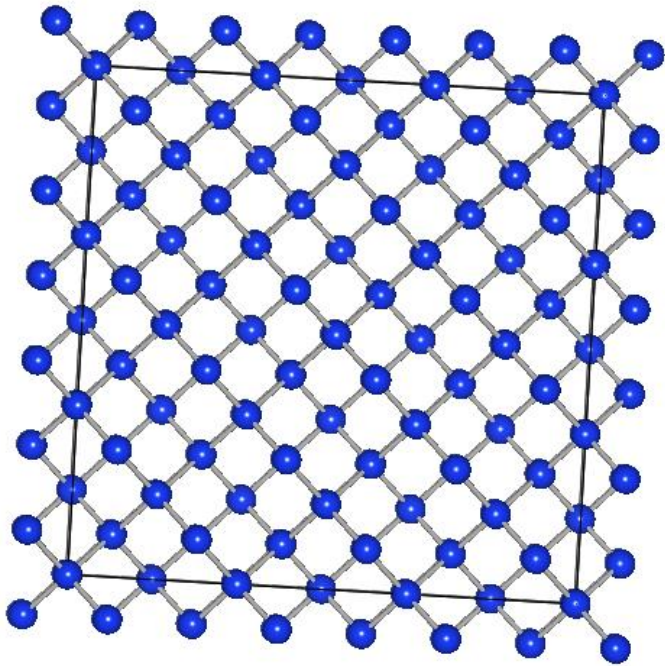
Introduction

- Atomic structure of amorphous materials
- Wooten, Winer, and Weaire (WWW) algorithm
- Behrend Amorphous Modelling (BAM) code
 - Research, education
- Amorphous silicon (a-Si)
 - Semiconductor, solar cells
- Amorphous Interfaces
 - electronics

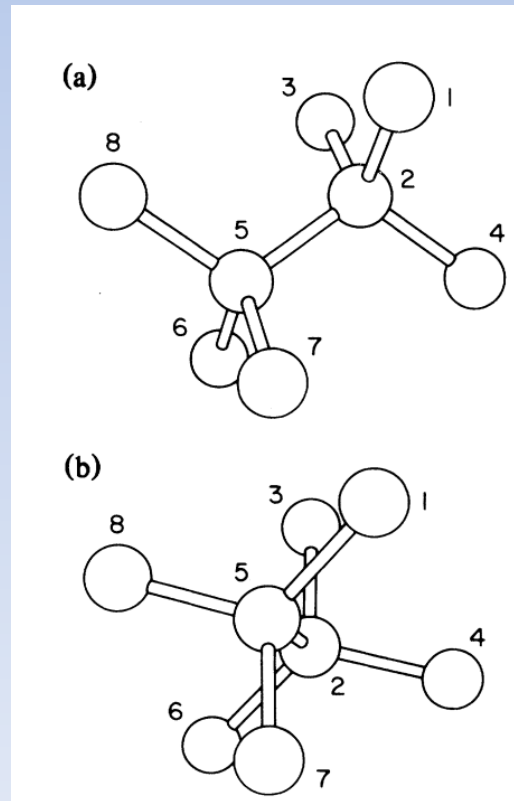
Amorphous Si

- Create low energy amorphous model
- Create models with defects
- Study electronic properties of defects in models

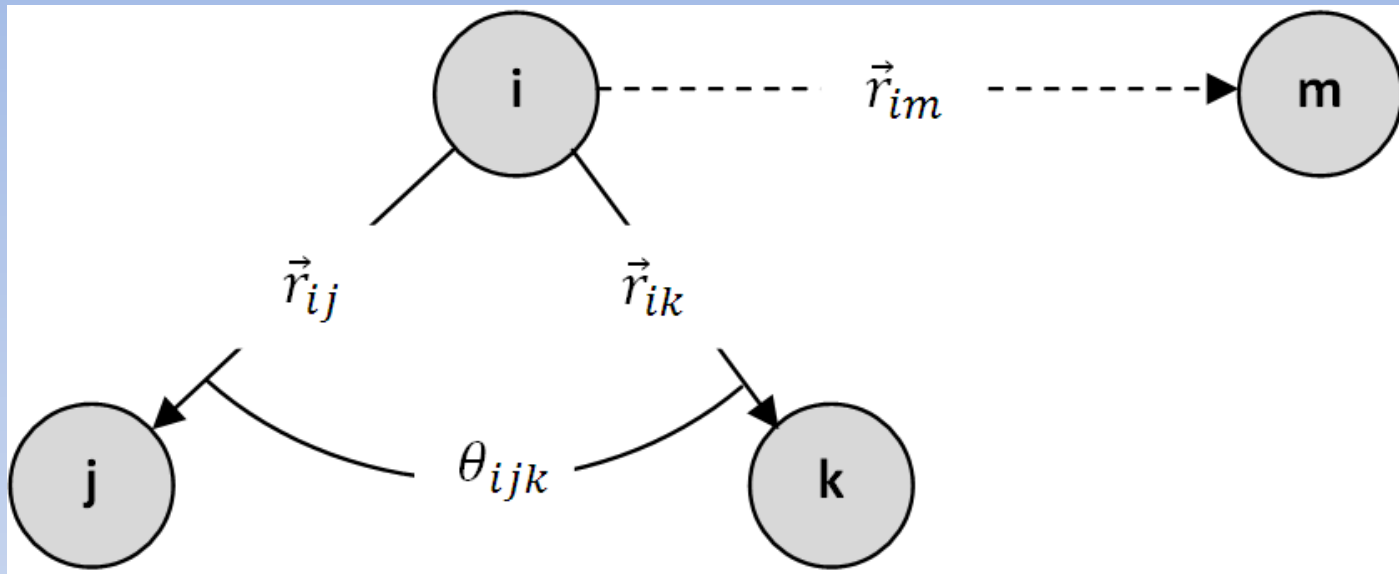
Starting Structure



Bond swapping



Energy: Keating Potential



$$PE_{radial} = \frac{1}{2} \sum_{i \in \alpha} \sum_{j \in \beta_i} \frac{1}{2} k_r (\|\vec{r}_{ij}\| - r_0)^2$$

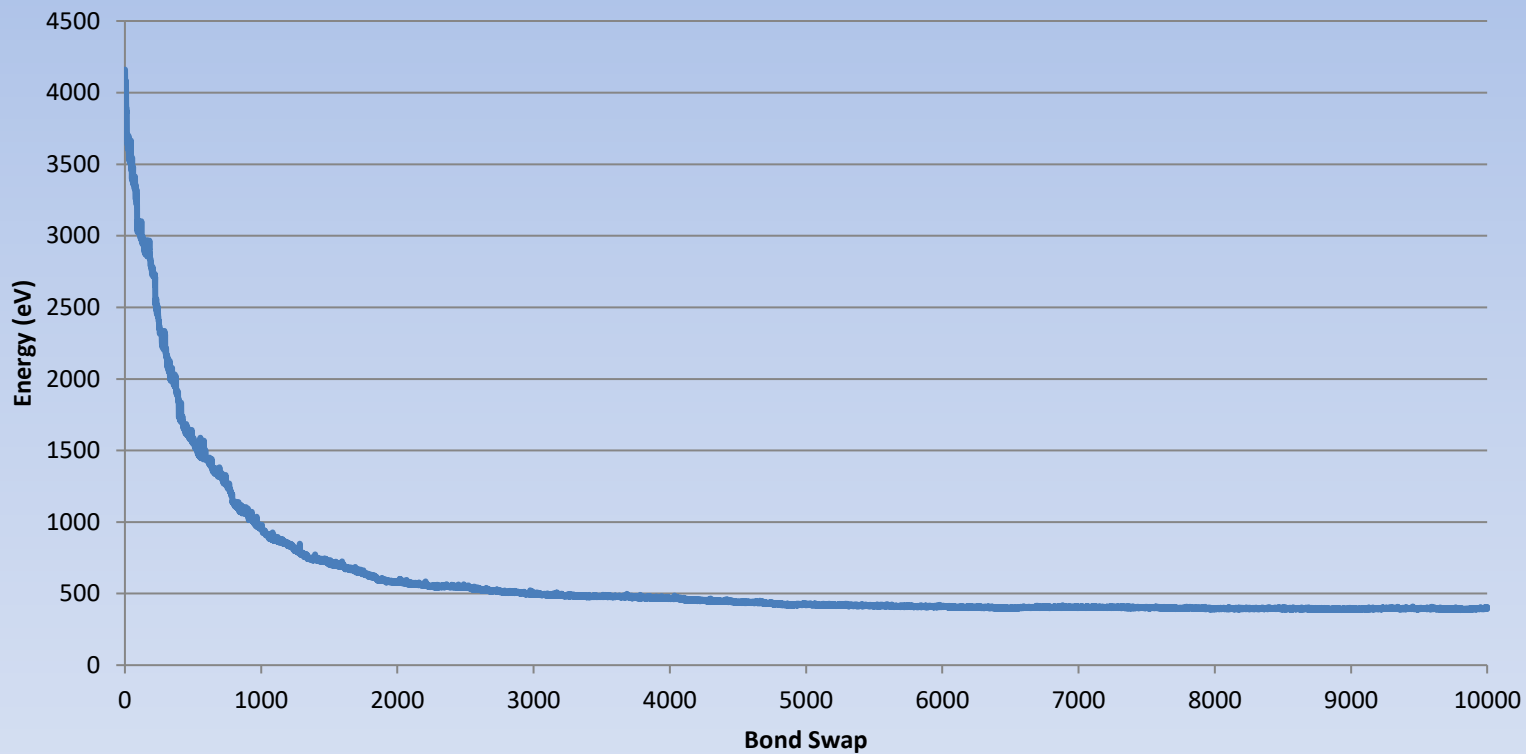
$$PE_{angular} = \sum_{i \in \alpha} \sum_{j \in \beta_i} \sum_{k \in \beta_i, k \neq j} \frac{1}{2} k_\theta (\cos \theta_{ijk} - \cos \theta_0)^2$$

$$PE_{repulsive} = \sum_{i \in \alpha} \sum_{m \in \beta_i, \|\vec{r}_{im}\| < d_0} \sigma (d_0 - \|\vec{r}_{im}\|)^3$$

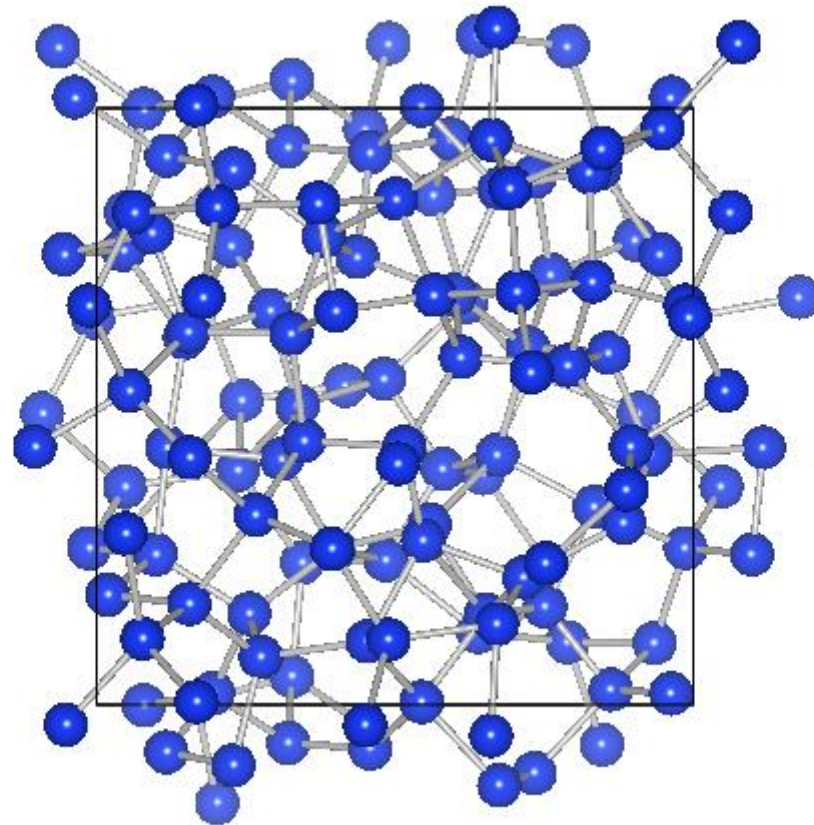
Simulation

- Bond swap
- Structure is relaxed using the Keating potential
- Metropolis Acceptance Probability (MAP)
 - $P = \exp[-\Delta E/kT]$ if $dE > 0$, $P = 1$ if $dE < 0$

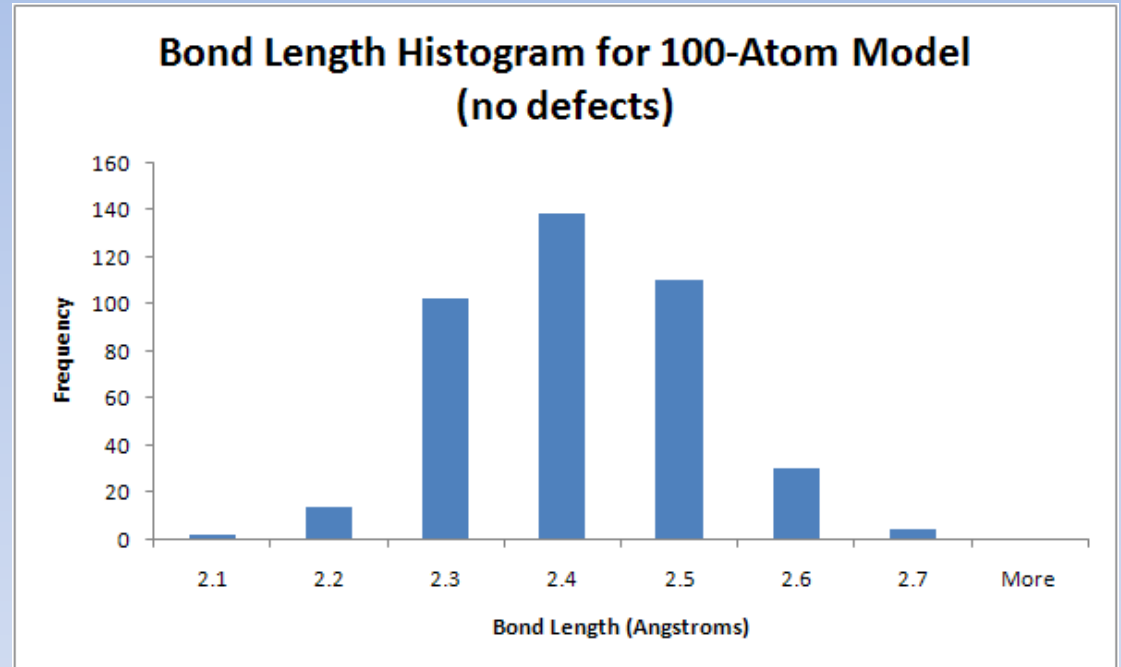
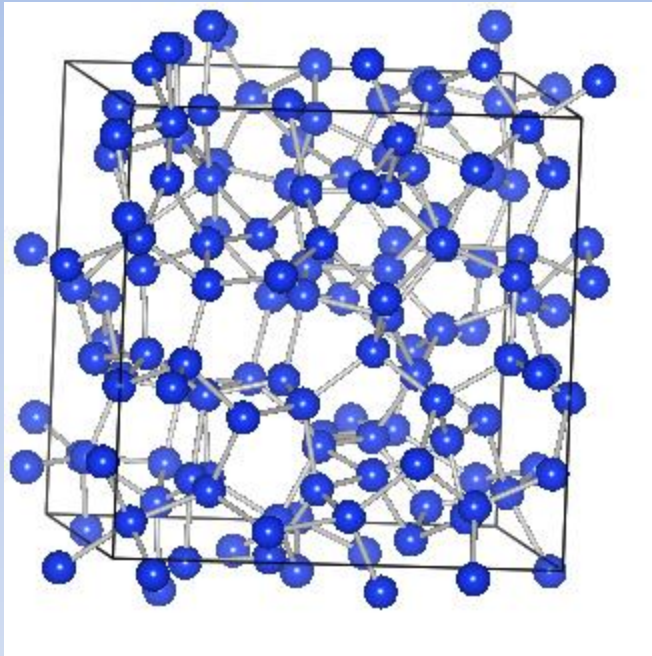
Energy vs. Number of Bond Swaps for One Cooling Run of the 216-Atom Crystal



100 Si Atoms ($kT=0.25$)

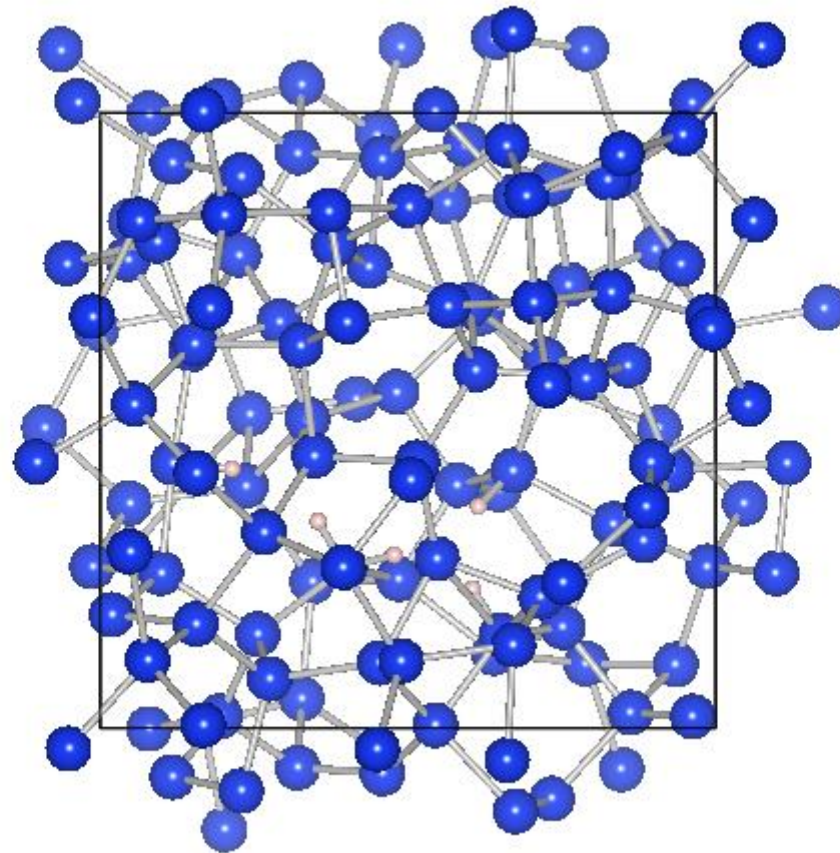


Final Model



*Generate models to study defects and H in amorphous Si

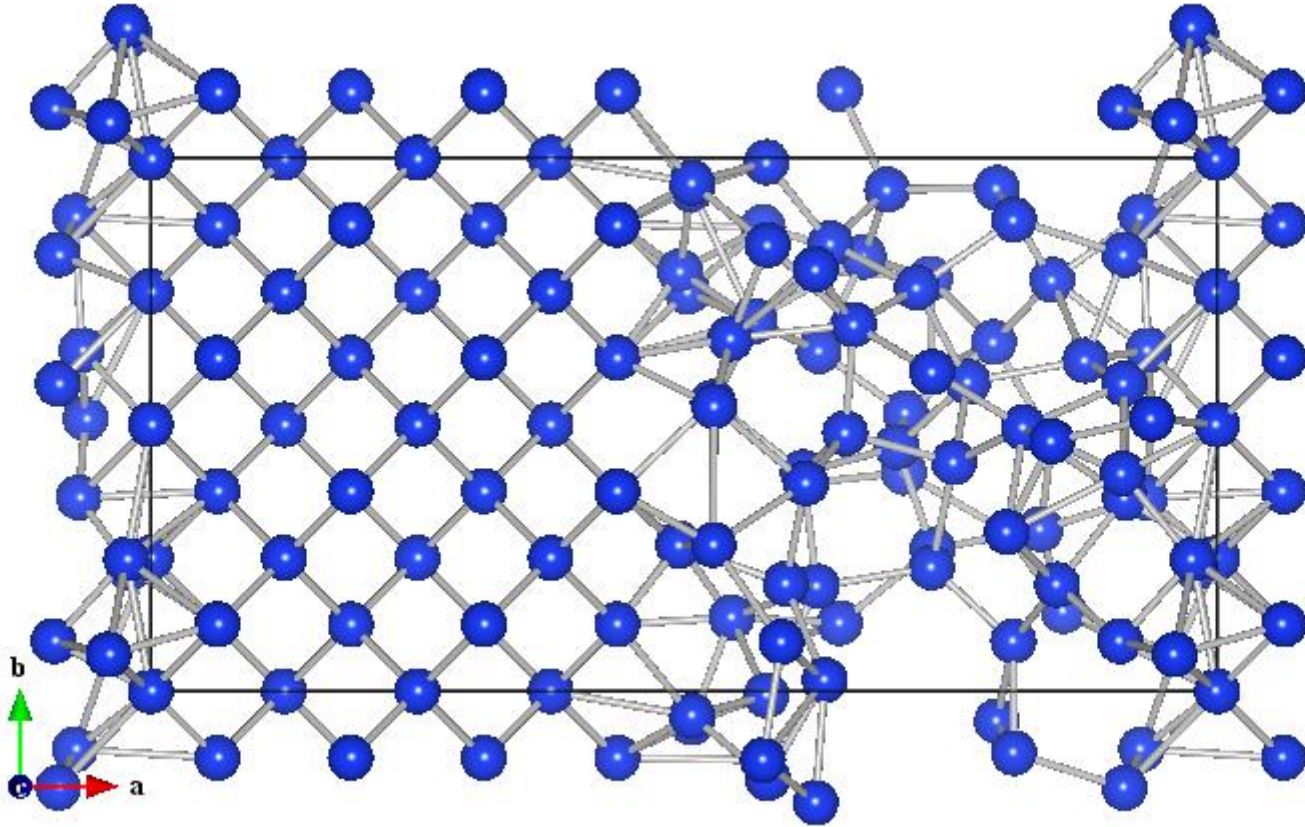
100 Si Atoms with Added H Atoms ($kT=0.25$)



Test Amorphous Si Model Data

#	N(Si)	E[BAM]	ΔE (VASP)	% ΔE
1	100	61	6.1	10.0
2	100	69	6.7	9.7
3	100	76	1.8	2.4
4	100	48	7.4	15.4
5	200	173 (87)	12.3	7.1
6	200	149 (75)	13.7	9.2
7	200	150 (75)	14.6	9.7

Crystalline Si / Amorphous Si Interface



Next Steps for Amorphous Si

- Analyze the electronic properties to ensure accuracy
- Calculate hyperfine parameters